

ERRATUM

Fast Solid State Electron Detectors Based on the Principle of Silicon Drift Detectors for Efficient Soft and Hard Matter Analysis – ERRATUM

A. Liebel, G. Lutz, U. Weber, A. Niculae, H. Soltau

doi:10.1017/S143192761501507X, Published by Cambridge University Press, 3 August 2015.

“Fast Solid State Electron Detectors Based on the Principle of Silicon Drift Detectors for Efficient Soft and Hard Matter Analysis” by Liebel et al. originally published with an incorrect DOI (doi:10.1017/S1431927615011617) which is a duplicate of “High-Resolution Phase-Contrast Imaging at XFELs” by Schropp et al. Liebel et al.’s paper has since been provided with a new, corrected DOI (doi:10.1017/S143192761501507X), and this has been corrected in the online version.

We apologize for the error.

References

- [1] Schropp, A. et al. (2015). High-Resolution Phase-Contrast Imaging at XFELs. *Microsc Microanal* **21**, Suppl 3, doi:10.1017/S1431927615011617.
- [2] Liebel, A. et al. (2015). Fast Solid State Electron Detectors Based on the Principle of Silicon Drift Detectors for Efficient Soft and Hard Matter Analysis. *Microsc Microanal* **21**, Suppl 3, doi: 10.1017/S143192761501507X.